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Application/Control No.	Applicant(s)/Patent under Reexamination
09/900,842	FREED, ERIK J.
Examiner	Art Unit
VAN H. NGUYEN	2194

SEARCHED				
Class	Subclass	Date	Examiner	
719	310,317	8/27/2005	VN	
709	202	8/27/2005	VN	
-				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
INVENTOR NAME SEARCH	8/27/2005	VN		
WEST (SEE SEARCH HISTORY PRINTOUT	8/27/2005	VN		
IEEE (SEE SEARCH HISTORY PRINTOUT)	8/27/2005	VN		
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